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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
I.	SAFETY TESTIN		ION 1 & 2	
1.	SAFETY TESTIN	GFRACILITY		
1.	Information Technology Equipments	Components	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 1.5 IEC 60950-1: 2005 Amd. 1: 2009	Qualitative Test
		Power Interface	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 1.6 IEC 60950-1: 2005 Amd. 1: 2009	0.01 W to 9999.99 W 0.1 A to 50 A
		Verifications of Marking & Instructions	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 1.7 IEC 60950-1: 2005 Amd. 1: 2009	Qualitative Test
		Protection From Electric Shock And Energy Hazards	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 2.1 IEC 60950-1: 2005 Amd. 1: 2009	Up to 200 N Upto 20 mA 200 mV to 1000 V (DC) 200 mV to 750 V (AC)
		SELV Circuits	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 2.2 IEC 60950-1: 2005 Amd. 1: 2009	Upto 300 V DC Upto 500 V AC
		TNV Circuits	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 2.3 IEC 60950-1: 2005 Amd. 1: 2009	Upto 120 V Upto 1200 Ω

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Information Technology Equipments	Limited Current Circuits	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 2.4 IEC 60950-1: 2005 Amd. 1: 2009	1 μA to 20 mA
		Limited Power Sources	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 2.5 IEC 60950-1: 2005 Amd. 1: 2009	Upto 300 V Upto 10 A
		Provisions For Earthing and Bonding	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 2.6 IEC 60950-1: 2005 Amd. 1: 2009	Upto 100 V Upto 5 mA 0.01 s to 300 s
		Overcurrent And Earth Fault Protection In Primary Circuits	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 2.7 IEC 60950-1: 2005 Amd. 1: 2009	0.1 A to 50 A 0.01 s to 9999 h
		Safety Interlocks	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 2.8 IEC 60950-1: 2005 Amd. 1: 2009	Qualitative
	Electrical Insulation	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 2.9 IEC 60950-1: 2005 Amd. 1: 2009	(20 %RH to 99 %RH) 0.1%RH 10 °C to 50 °C 0.01 kV to 10 kV 1s to 9999 h/0.01 s	

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Information Technology Equipments	Clearances, Creepage Distances And Distances Through Insulation	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 2.10 IEC 60950-1: 2005 Amd. 1: 2009	Upto 50 mm
		Wiring, Connections and Supply	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 3 IEC 60950-1: 2005 Amd. 1: 2009	200 mV to 1000 V (DC) 200 mV to 750 V (AC)
		Connection to a Main Supply	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 3.2 IEC 60950-1: 2005 Amd. 1: 2009	Upto 100 N
		Wiring Terminals for Connection of External Conductors	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 3.3 IEC 60950-1: 2005 Amd. 1: 2009	0.01 mm to 300 mm
		Disconnection for the Main Supply	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 3.4 IEC 60950-1: 2005 Amd. 1: 2009	Qualitative
		Interconnection of Equipment	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 3.5 IEC 60950-1: 2005 Amd. 1: 2009	Qualitative

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Information Technology Equipments	Stability	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 4.1 IEC 60950-1: 2005 Amd. 1: 2009	10° to 15° 1 N to 200 N
		Mechanical Strength	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 4.2 IEC 60950-1: 2005 Amd. 1: 2009	Upto 500 N
		Design and Construction	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 4.3 IEC 60950-1: 2005 Amd. 1: 2009	Upto 30 mm Upto 500 g
		Protection Against Hazardous Moving Parts	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 4.4 IEC 60950-1: 2005 Amd. 1: 2009	Qualitative
		Thermal Requirements	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 4.5 IEC 60950-1: 2005 Amd. 1: 2009	Upto 300 °C Upto 20 kΩ
		Openings In Enclosures	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 4.6 IEC 60950-1: 2005 Amd. 1: 2009	0.01 mm to 300 mm

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Information Technology Equipments	Resistance To Fire	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 4.7 IEC 60950-1: 2005 Amd. 1: 2009	Mass 20 N, Ball: 5 mm, 9.5 mm, 0.5 mm 1 ms to 99.99 min Upto 20 mA AC Upto 4 kVac
		Electrical Requirements and Simulated Abnormal Conditions	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 5 IEC 60950-1: 2005 Amd. 1: 2009	2 mA to 20 mA AC
		Electric Strength	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 5.2 IEC 60950-1: 2005 Amd. 1: 2009	Qualitative (Upto 5 kVac)
		Abnormal Operating and Fault Conditions	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 5.3 IEC 60950-1: 2005 Amd. 1: 2009	Upto 300 °C Upto 20 mA AC
		Connection to Telecommunication Networks	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 6 IEC 60950-1: 2005 Amd. 1: 2009	Upto 20 kV Upto 5 kVac
		Connection To Cable Distribution Systems	IS 13252 (Part 1): 2010 Amd. 1: 2013 Cl. No. 7 IEC 60950-1: 2005 Amd. 1: 2009	Upto 1000 MΩ Upto 10 kV

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
2.	Medical Devices	Power Input	IEC 60601-1: 2005 Cl. No. 4.11 IS 13450-1: 2008	0.01 W to 9999.99 W
		Marking And Instructions	IEC 60601-1: 2005 Cl. No. 7 IS 13450-1: 2008	Qualitative
		Determination Of Accessible Parts	IEC 60601-1: 2005 Cl. No. 5.9 IS 13450-1: 2008	Qualitative
		Protective Earthing, Functional Earthing, Potential Equalization, Surface Coating, Plugs & Sockets, Functional Earth Terminal	IEC 60601-1: 2005 Cl. No. 8.6 IS 13450-1: 2008	Qualitative
		Leakage Currents And Patients Auxiliary Currents	IEC 60601-1: 2005 Cl. No. 8.7 IS 13450-1: 2008	1 μA to 20 mA
		Dielectric Strength	IEC 60601-1: 2005 Cl. No. 8.8 IS 13450-1: 2008	0.2 kV to 20 kV
		Resistance To Environmental Stress	IEC 60601-1: 2005 Cl. No. 8.8.4.2 IS 13450-1: 2008	Qualitative

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	Medical Devices	Accessible Parts Including Applied Part	IEC 60601-1: 2005 Cl. No. 5.9 IS 13450-1: 2008	Qualitative
		Creepage Distances And Air Clearance	IEC 60601-1: 2005 Cl. No. 8.9 IS 13450-1: 2008	0.01 mm to 300 mm
3.	Electronics Audio, Video and Similar	Verifications of Marking And Instructions	IS 616 : 2010 Cl. No. 5 IEC 60065: 2005	Qualitative
	Similar Electronic Apparatus	Hazardous Radiations	IS 616 : 2010 Cl. No. 6 IEC 60065: 2005	0.1 mR/ H to 100 mR/H
		Heating Under Normal Operating Conditions	IS 616 : 2010 Cl. No. 7 IEC 60065: 2005	Upto 200 °C Upto 20 kΩ
		Constructional Requirements With Regard To The Protection Against Electric Shock	IS 616 : 2010 Cl. No. 8 IEC 60065: 2005	As per Figs Upto 200 N 0 to 20 mA 0 to 25 mA, 12 V DCV: 200 mV to 1000 V ACV: 200 mV to 750 V 0 to 5 kVac 0 to 200 mm
		Electric Shock Hazard Under Normal Operating Condition	IS 616 : 2010 Cl. No. 9 IEC 60065: 2005	Qualitative

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Electronics Audio, Video and Similar Electronic	Insulation Requirements	IS 616 : 2010 Cl. No. 10 IEC 60065: 2005	$\begin{array}{c} 0 \text{ to } 10 \text{ kV} \\ 1000 \text{ M}\Omega \\ 0 \text{ to } 5 \text{ kV AC} \end{array}$
	Apparatus	Fault Conditions	IS 616 : 2010 Cl. No.11 IEC 60065: 2005	Upto 200 °C Upto 20 kΩ
		Mechanical Strength	IS 616 : 2010 Cl. No. 12 IEC 60065: 2005	0 to 200 N 0 to 5 Nm
		Clearances and Creepage Distances	IS 616 : 2010 Cl. No. 13 IEC 60065: 2005	0 to 50 mm
		Components	IS 616 : 2010 Cl. No. 14 IEC 60065: 2005	Qualitative
		Terminals	IS 616 : 2010 Cl. No. 15 IEC 60065: 2005	(1 Nm to 10 Nm)/0.1 Nm
		External Flexible Cords	IS 616 : 2010 Cl. No. 16 IEC 60065: 2005	0 to 200 mm 0 to 25 Nm
		Electrical Connections and Mechanical Fixings	IS 616 : 2010 Cl. No. 17 IEC 60065: 2005	35 A, 7 kg 0 to 2.5 Nm
		Stability and Mechanical Hazards	IS 616 : 2010 Cl. No. 19 IEC 60065: 2005	0 to 200 N

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	Electronics Audio, Video and Similar Electronic Apparatus	Resistance to Fire	IS 616 : 2010 Cl. No. 20 IEC 60065: 2005	Mass 20 N, Ball Dia: 5 mm, 9.5 mm 0.5 mm 1 ms to 99.99 min
4.	Instruments For Measurement And Laboratory Use	Testing In Single Fault Condition	IEC 61010-1: (2010-06) Cl. No. 4.4	Qualitative
		Durability Of Markings	IEC 61010-1: (2010-06) Cl. No. 5.3	Qualitative
	Microscopes, Power Supply, Auto Transformer	Determination Of Accessible Parts	IEC 61010-1: (2010-06) Cl. No. 6.2	Qualitative
	Electrical Laboratory Equipment, Signal	Protective Bonding	IEC 61010-1: (2010-06) Cl. No. 6.5.2	Qualitative
	Generators, Transducers, Transmitters)	Insulation Requirements	IEC 61010-1: (2010-06) Cl. No. 6.7	Qualitative (0.01 M Ω to 1 G Ω At 500 V DC & 1000 V DC)
		Procedure For Voltage Test	IEC 61010-1: (2010-06) Cl. No. 6.8	Qualitative
		Clearance & Creepage Distance	IEC 61010-1: (2010-06) Cl. No. 6.7	0.01 mm to 300 mm

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Instruments For Measurement And	Drop Test	IEC 61010-1: (2010-06) Cl. No. 8.3	Qualitative
	Laboratory Use (Electrical Control Equipment,	Resistance To Heat	IEC 61010-1: (2010-06) Cl. No. 10.5	Quantitative
	Electrical Microscopes, Power Supply,	Transient Overvoltage Limiting Device	IEC 61010-1: (2010-06) Cl. No. 14.9	Qualitative
	Auto Transformer Electrical Laboratory Equipment, Signal Generators, Transducers, Transmitters)	Specially Protected Equipment	IEC 61010-1: (2010-06) Cl. No. 11.6	Qualitative
II.	POWER SUPPLIE	ES AND STABILIZERS		
1.	Uninterruptible Power Supply (UPS)	Protective Earthing & Bonding	IEC 62040-1: 2008 Cl. No. 5.3 IS 16242 (Part 1): 2014 Cl. No. 5	Qualitative
		AC and DC Power Isolation	IEC 62040-1: 2008 Cl. No. 5.4 IS 16242 (Part 1): 2014 Cl. No. 5.4	Qualitative
		Over-Current & Earth- Fault Protection	IEC 62040-1: 2008 Cl. No. 5.5 IS 16242 (Part 1): 2014 Cl. No. 5.5	Qualitative (0.1 A to 50 A) A

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Uninterruptible Power Supply (UPS)	Protection Of Personnel- Safety Interlocks	IEC 62040-1: 2008 Cl. No. 5.6 IS 16242 (Part 1): 2014 Cl. No. 5.6	Qualitative
		Wiring, Connections & Supply	IEC 62040-1: 2008 Cl. No. 6 IS 16242 (Part 1): 2014 Cl. No. 6	Qualitative
		Physical Requirements	IEC 62040-1: 2008 Cl. No. 7 IS 16242 (Part 1): 2014 Cl. No. 7	Qualitative (0.1 °C to 1200 °C
		Electrical Requirements & Simulated Abnormal Conditions	IEC 62040-1: 2008 Cl. No. 8 IS 16242 (Part 1): 2014 Cl. No. 8	1 μA to 20 mA
III.	DOMESTIC ELI	ECTRONIC APPLIANCES & A	ACCESSORIES	
1.	Domestic Electric Clothes Washing Machine	Safety Requirements	IS 302-2-7: 2012 Cl. No. 8 to 32	Qualitative
	Machine	Determination of Washing Performance	IS 14155: 1994 Cl. No. 11	Upto 80 %
		Determination of Wear Suffered by Textile	IS 14155: 1994 Cl. No. 12	Upto 80 % 1 mm to 5000 mm
		Determination of Rinsing Efficiency	IS 14155: 1994 Cl. No. 13	Upto 1000 milli equivalent/l 1 g to 200 kg

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Domestic Electric Clothes Washing Machine	Determination of Water Extracting Efficiency	IS 14155: 1994 Cl. No. 14	1 g to 200 kg
		Determination of Mechanical Detergent Loss in the Sump of Washing Machine	IS 14155: 1994 Cl. No. 16	0.01 g to 200 g
		Determination of Water and Energy Consumption	IS 14155: 1994 Cl. No. 15	0.1 kWh to 9999.9 kWh 0.01 m ³ /s to 99.9 m ³ /s
		Endurance	IS 14155: 1994 Cl. No. 17	Qualitative
		Finish	IS 14155: 1994 Cl. No. 18	Qualitative
IV.	ENVIRONMENTA	AL TEST FACILITY		
1.	Environmental Testing For IT, Electronic & Electrical Items	Dry Heat and Cold Test	IS 9000 (Part 2/Sec I to IV): 1977 IS 9000 (Part 3/Sec I to V): 1977 IEC 60068-2-1: 2007 IEC 60068-2-2: 2007	0.1 kWh to 9999.9 kWh 0.01 m³/s to 99.9 m³/s Qualitative Qualitative (Ambient to 25 °C) Qualitative
		Composite Temperature/ Humidity Cyclic Test	IS 9000 (Part 6): 1978 IEC 68-2-38	Qualitative
		Impact Test	IS 9000 (Part 7/Sec I): 2006 IS 9000 (Part 7/Sec I to V): 1979 IS 9000 (Part 7/Sec VI): 1988 IS 9000-7-7: 2006 IEC 60068-2-27 IEC Pub 68-2-27: 2009 IEC Pub 68-2-31: 2008 IEC 60068-2-55: 2013 IEC 60068-2-75: 1997	Qualitative

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	Environmental Testing For IT,	Low Air Pressure Test	IS 9000 (Part 13): 1981	Qualitative		
	Electronic & Electrical Items	Change Of Temp	IS 9000 (Part 14/Sec I to III): 1988	Qualitative		
v.	EMC/EMI TEST FACILITY					
1.	Information technology equipment	Conducted Disturbance Voltage	Information technology equipment - Radio disturbance characteristics - Limits and methods of measurement CISPR 22:2008 EN 55022:2010	150 kHz to 30 MHz		
2.	Audio, video and associated equipment	Conducted Disturbance Voltage	Sound and Television Broadcast Receivers and Associated Equipment - Radio	150 kHz to 30MHz		
	• •	Disturbance Power	Disturbance Characteristics - Limits and Methods of Measurement CISPR 13:2009 EN 55013:2013	30 MHz to 300 MHz		
3.	Household appliances, electric tools and similar apparatus	Disturbance Power	CISPR 14-1: 2005+A1:2008+A2:2011 EN 55014-1: 2006+A1:2009+A2:2011	30 MHz to 300 MHz		

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S.No.	Product / Material of Test	Specific Test Performed	Test Method Specification against which tests are performed	Range of Testing / Limits of Detection
	Household appliances, electric tools and similar apparatus	Conducted Disturbance	Household appliances, electric tools and similar apparatus - CISPR 14-1: 2005+A1:2008+A2:2011 EN 55014-1: 2006+A1:2009+A2:2011	150 kHz to 30 MHz
4.	Lighting Equipment	Radiation Disturbance	Limits and methods of measurement of radio disturbance characteristics of electrical lighting and similar equipment EN 55015:2013	150 kHz to 30 MHz
		Radiated electromagn-etic disturbances	Limits and methods of measurement of radio disturbance characteristics of electrical lighting and similar equipment EN 55015:2013	150 kHz to 30 MHz
5	Industrial, scientific and medical equipment	Conducted Disturbance Voltage	Industrial, scientific and medical (ISM) CISPR 11:2009+A1:2010 EN 55011:2009+A1:2010	150 kHz to 30 MHz
6.	Electric/ electronic products used in residential, commercial and light-industrial environments	Conducted Disturbance Voltage	Residential, commercial and light-industrial environments IEC 61000-6-3:2006+A1:2010 EN 61000-6-3:2007+A1:2011	150 kHz to 30 MHz

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7.	Electric/ electronic products used in industrial environ-ments	Conducted Disturbance Voltage	Electromagnetic compatibility (EMC) - Part 6-4:Generic standards - Emission standard for industrial environments IEC 61000-6-4:2006+A1:2010 EN 61000-6-4:2007+A1:2011	150 kHz to 30 MHz	
8.	Radio frequency devices	Conducted Disturbance Voltage	Radio frequency devices FCC PART 15:2013	150 kHz to 30 MHz	
VI.	TELECOM PRODUCTS				
1.	Telecom Products: Telephones /Analog Modems/Digital Modems/T1/E1/A	Surge	TIA 968-B IC CS-03 Issue 9	Metallic Voltage Surge - Type A: (800 Volts, 100A, 10/560 uS.) Longitudinal Voltage Surge - Type A: (1500	
	DSL			Volts, 200A, 10/160 uS.)	
				Metallic Voltage Surge - Type B: (1000 Volts, 25A, 9/720uS)	
				Longitudinal Voltage Surge - Type B: (1500 Volts, 37.5A, 9/720uS)	
				Power Line Surge: (2500 V, 2/10 uS.)	

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	Telecom Products: Telephones	Leakage Current	TIA 968-B IC CS-03 Issue 9	1000V & 10mA
	/Analog Modems/Digital Modems/T1/E1/A	Signal Power Limitations	TIA 968-B IC CS-03 Issue 9	100 Hz to 30 MHz
	DSL	Longitudinal Balance	TIA 968-B IC CS-03 Issue 9	200 Hz to 4kHz
		On Hook Impedance	TIA 968-B IC CS-03 Issue 9	Qualitative
		Pulse Shape	TIA 968-B IC CS-03 Issue 9	T1,E1, DSL

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